Amendments to the Claims:

This listing of claims will replace all prior listings of claims in the application.

1. (original). An illumination apparatus comprising:

an inner-surface reflecting type integrator;

an optical system for directing a beam from a light source to a portion of

incidence of said inner-surface reflecting type integrator;

an wave-front splitting type integrator;

an image-forming optical system for arranging the portion of incidence of said

inner-surface reflecting type integrator approximately conjugate with a portion of incidence of

said wave-front splitting type integrator, and for directing a beam from said beam mixer to said

wave-front splitting type integrator; and

an irradiating optical system for superimposing multiple beams from said wave-

front splitting type integrator on a plane to be irradiated, wherein a stop is provided at or near the

portion of exit of said inner-surface reflecting type integrator.

2. (original). An illumination apparatus according to claim 1, wherein said inner-surface

reflecting optical integrator reflects at least a part of incident light with an internal surface of said

inner-surface reflecting optical integrator, and for forming a surface light source on or near the

plane of exit of said inner-surface reflecting optical integrator.

3. (original). An illumination apparatus according to claim 1, wherein said wave-front splitting

type integrator is a lens array for splitting a wave front of incident light, and for forming multiple

secondary light sources on or near the portion of exit of said wave-front splitting type integrator.

-2 of 8-

Appl. No. 10/053,191

Paper dated September 5, 2003

4. (original). An illumination apparatus according to claim 1, wherein said stop is a mechanical

aperture stop.

5. (original). An illumination apparatus according to claim 1, wherein said stop is made of a

light shielding material applied onto the portion of exit of said inner-surface reflecting type

integrator.

6. (original). An illumination apparatus according to claim 1, wherein said stop is made of a

multi-layer film vapor-deposited onto the portion of exit of said inner-surface reflecting type

integrator.

7. (original). An illumination apparatus according to claim 1, wherein said stop is made of a

metallic film vapor-deposited onto the portion of exit of said inner-surface reflecting type

integrator.

8. (currently amended). An illumination apparatus according to claim 1-7 1, wherein said

image-forming system is a zoom optical system.

9. (currently amended). An illumination apparatus according to claim 1 or 8, wherein the

portion of exit of said inner-surface reflecting type integrator has a polygonal shape, and said

stop has an aperture for correcting σ anisotropy.

10. (original). An illumination apparatus according to claim 9, wherein said stop has an

approximately circular aperture.

11. (cancelled).

(original). An illumination apparatus comprising;

an inner-surface reflecting type integrator including a portion of exit with an n-

gonal shape where n is a natural number;

a wave-front splitting type integrator;

-3 of 8-

Appl. No. 10/053,191

Paper dated September 5, 2003

a zoom optical system for projecting an image of the portion of exit of said inner-

surface reflecting type integrator, onto a portion of incidence of said wave-front splitting

integrator; and

an irradiating optical system for superimposing multiple beams from said wave-

front splitting integrator on a plane to be irradiated, wherein a stop having an approximately

circular aperture is provided at or near the portion of exit of said inner-surface reflecting type

integrator.

13. (cancelled).

14. (original). A projection exposure apparatus comprising:

an illumination apparatus for illuminating a mask located on a plane to be

illuminated; and

a projection optical system for projecting a pattern on said mask onto a wafer,

wherein said illumination apparatus comprising:

an inner-surface reflecting type integrator;

an optical system for directing a beam from a light source to a portion of

incidence of said inner-surface reflecting type integrator;

an wave-front splitting type integrator;

an image-forming optical system for arranging the portion of incidence of said

inner-surface reflecting type integrator approximately conjugate with a portion of incidence of

said wave-front splitting type integrator, and for directing a beam from said beam mixer to said

wave-front splitting type integrator; and

-4 of 8-

an irradiating optical system for superimposing multiple beams from said wavefront splitting type integrator on a plane to be irradiated, wherein a stop is provided at or near the portion of exit of said inner-surface reflecting type integrator.

15. (original). A projection exposure apparatus comprising:

an illumination apparatus for illuminating a mask located on a portion to be illuminated; and

a projection optical system for projecting a pattern on said mask onto a wafer, wherein said illumination apparatus comprising:

an inner-surface reflecting type integrator including a portion of exit with an n-gonal shape where n is a natural number;

a wave-front splitting type integrator;

a zoom optical system for projecting an image of the portion of exit of said innersurface reflecting type integrator, onto a portion of incidence of said wave-front splitting integrator; and

an irradiating optical system for superimposing multiple beams from said wavefront splitting integrator on a plane to be irradiated, wherein a stop having an approximately circular aperture is provided at or near the portion of exit of said inner-surface reflecting type integrator.

16. (cancelled).

17. (original). A device fabrication method comprising the steps of:

projecting a pattern on a mask onto a wafer by using a projection exposure apparatus; and

developing said wafer to which said pattern was transferred,

-5 of 8-

wherein said projection exposure apparatus comprising:

an illumination apparatus for illuminating a mask located on a plane to be

illuminated; and

a projection optical system for projecting a pattern on said mask onto a wafer,

wherein said illumination apparatus comprising:

an inner-surface reflecting type integrator;

an optical system for directing a beam from a light source to a portion of

incidence of said inner-surface reflecting type integrator;

an wave-front splitting type integrator;

an image-forming optical system for arranging the portion of incidence of said

inner-surface reflecting type integrator approximately conjugate with a portion of incidence of

said wave-front splitting type integrator, and for directing a beam from said beam mixer to said

wave-front splitting type integrator; and

an irradiating optical system for superimposing multiple beams from said wave-

front splitting type integrator on a plane to be irradiated, wherein a stop is provided at or near the

portion of exit of said inner-surface reflecting type integrator.

18. (original). A device fabrication method comprising the steps of:

projecting a pattern on a mask onto a wafer by using a projection exposure

apparatus: and

developing said wafer to which said pattern was transferred,

wherein said projection exposure apparatus comprising:

an illumination apparatus for illuminating a mask located on a plane to be

illuminated: and

-6 of 8-

792848 v1

Appl. No. 10/053,191 Paper dated September 5, 2003

a projection optical system for projecting a pattern on said mask onto a wafer,

wherein said illumination apparatus comprising:

an inner-surface reflecting type integrator including a portion of exit with an n-

gonal shape where n is a natural number;

a wave-front splitting type integrator;

a zoom optical system for projecting an image of the portion of exit of said inner-

surface reflecting type integrator, onto a portion of incidence of said wave-front splitting

integrator; and

an irradiating optical system for superimposing multiple beams from said wave-

front splitting integrator on a plane to be irradiated, wherein a stop having an approximately

circular aperture is provided at or near the portion of exit of said inner-surface reflecting type

integrator.

19. (cancelled).